

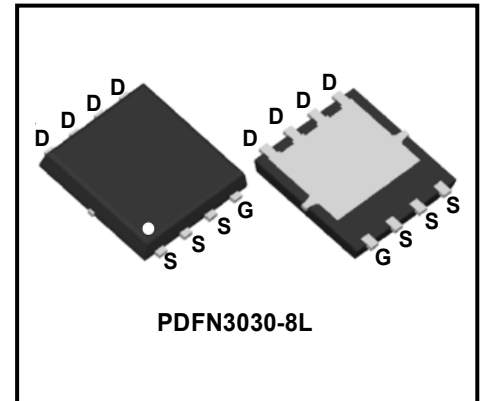
20V N-Channel Enhancement Mode Power MOSFET

Description

WMQ30N02T1 uses advanced power trench technology that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

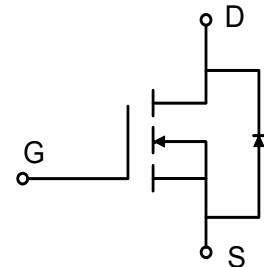
Features

- $V_{DS} = 20V$, $I_D = 75A$
 $R_{DS(on)} < 4m\Omega$ @ $V_{GS} = 4.5V$
 $R_{DS(on)} < 5m\Omega$ @ $V_{GS} = 2.5V$
- Low $R_{DS(on)}$
- Advanced High Cell Density Trench Technology
- 100% EAS Guaranteed



Applications

- Power Management Switches
- DC/DC Converter

Absolute Maximum Ratings ($T_A = 25^\circ C$, unless otherwise noted)

Parameter		Symbol	Value	Unit
Drain-Source Voltage		V_{DS}	20	V
Gate-Source Voltage		V_{GS}	± 10	V
Continuous Drain Current	$T_C = 25^\circ C$	I_D	75	A
	$T_C = 100^\circ C$		47.5	
Pulsed Drain Current ¹		I_{DM}	300	A
Single Pulse Avalanche Energy ²		EAS	125	mJ
Total Power Dissipation	$T_C = 25^\circ C$	P_D	37.8	W
Operating Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	$^\circ C$

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance from Junction-to- Ambient ³	$R_{\theta JA}$	60	$^\circ C/W$
Thermal Resistance from Junction-to-Case	$R_{\theta JC}$	3.3	$^\circ C/W$

Electrical Characteristics ($T_A = 25^\circ\text{C}$, unless otherwise noted)

Parameter		Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static Characteristics							
Drain-Source Breakdown Voltage		V _{(BR)DSS}	V _{GS} = 0V, I _D = 250μA	20	-	-	V
Gate-body Leakage current		I _{GSS}	V _{DS} = 0V, V _{GS} = ±10V	-	-	±100	nA
Zero Gate Voltage Drain Current	T _J =25°C	I _{DSS}	V _{DS} = 20V, V _{GS} = 0V	-	-	1	μA
	T _J =100°C			-	-	100	
Gate-Threshold Voltage		V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250μA	0.4	0.65	1	V
Drain-Source On-Resistance ⁴		R _{DS(on)}	V _{GS} = 4.5V, I _D = 20A	-	2.7	4	mΩ
			V _{GS} = 2.5V, I _D = 15A	-	3.3	5	
Forward Transconductance ⁴		g _{fs}	V _{GS} = 4.5V, I _D = 20A	-	139	-	S
Dynamic Characteristics ⁵							
Input Capacitance		C _{iss}	V _{DS} = 10V, V _{GS} =0V, f =1MHz	-	3560	-	pF
Output Capacitance		C _{oss}		-	510	-	
Reverse Transfer Capacitance		C _{rss}		-	440	-	
Gate Resistance		R _g	f =1MHz	-	2	-	Ω
Switching Characteristics ⁵							
Total Gate Charge		Q _g	V _{GS} = 4.5V, V _{DS} = 10V, I _D = 20A	-	43.8	-	nC
Gate-Source Charge		Q _{gs}		-	7.2	-	
Gate-Drain Charge		Q _{gd}		-	8.4	-	
Turn-On Delay Time		t _{d(on)}	V _{GS} =4.5V, V _{DD} = 10V, R _G = 3Ω, I _D = 20A	-	6.9	-	ns
Rise Time		t _r		-	3.9	-	
Turn-Off Delay Time		t _{d(off)}		-	65	-	
Fall Time		t _f		-	36	-	
Body Diode Reverse Recovery Time		t _{rr}	I _F = 20A, dI/dt = 100A/μs	-	44	-	ns
Body Diode Reverse Recovery Charge		Q _{rr}		-	14	-	nC
Drain-Source Body Diode Characteristics							
Diode Forward Voltage ⁴		V _{SD}	I _S = 20A, V _{GS} = 0V	-	-	1.2	V
Continuous Source Current	T _C =25°C	I _S	-	-	-	75	A

Notes:

1. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)} = 150^\circ\text{C}$.
2. The EAS data shows Max. rating. The test condition is $V_{DD} = 25V, V_{GS} = 10V, L = 0.4mH, I_{AS} = 25A$.
3. The data tested by surface mounted on a 1 inch² FR-4 board with 20Z copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed, pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.
5. This value is guaranteed by design hence it is not included in the production test.

Typical Characteristics

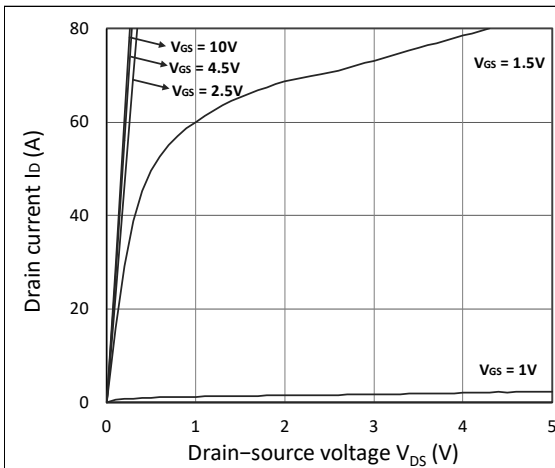


Figure 1. Output Characteristics

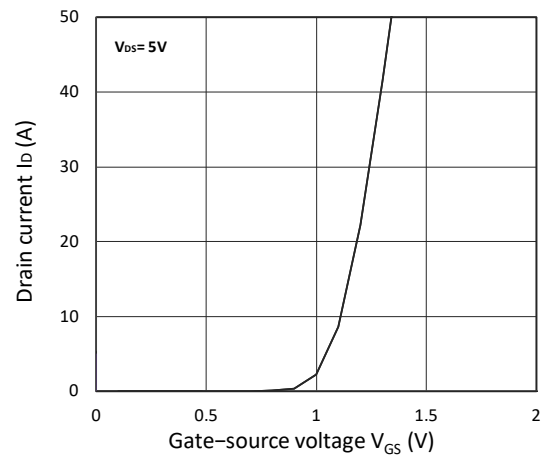


Figure 2. Transfer Characteristics

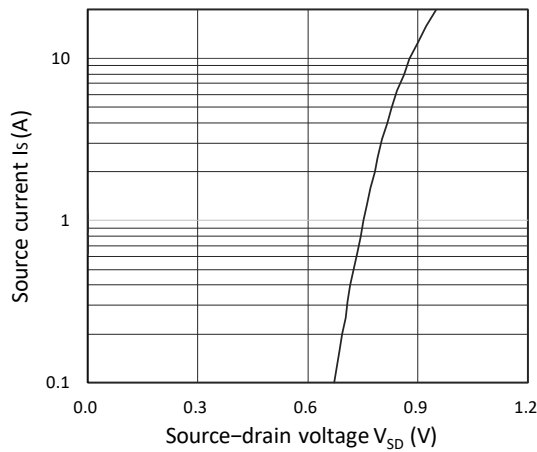
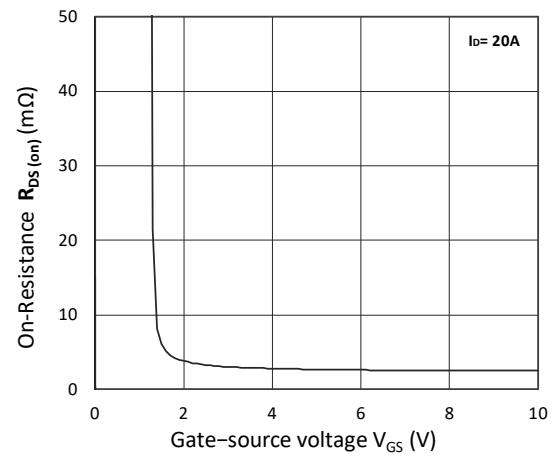
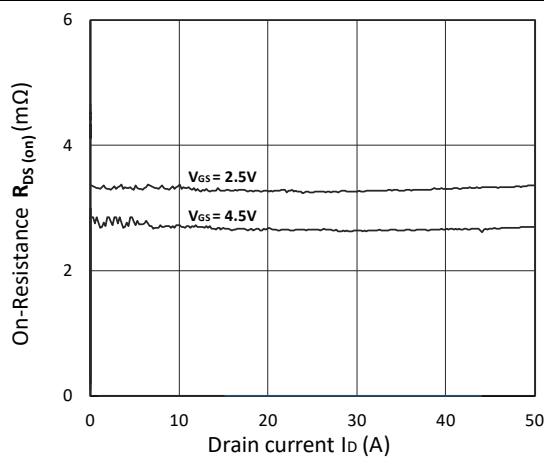
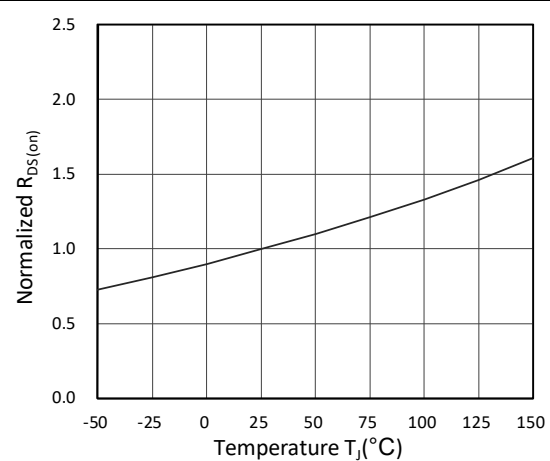


Figure 3. Forward Characteristics of Reverse

Figure 4. $R_{DS(on)}$ vs. V_{GS} Figure 5. $R_{DS(on)}$ vs. I_D Figure 6. Normalized $R_{DS(on)}$ vs. Temperature

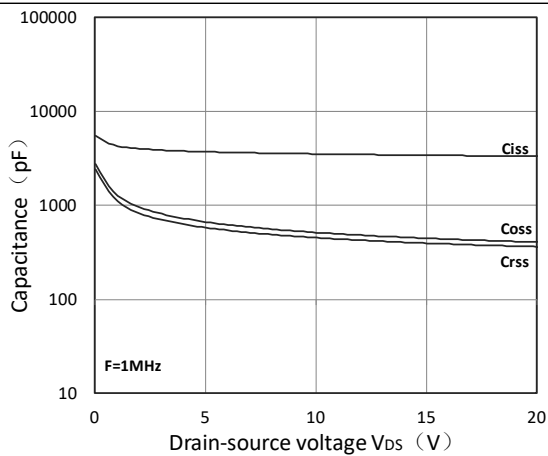


Figure 7. Capacitance Characteristics

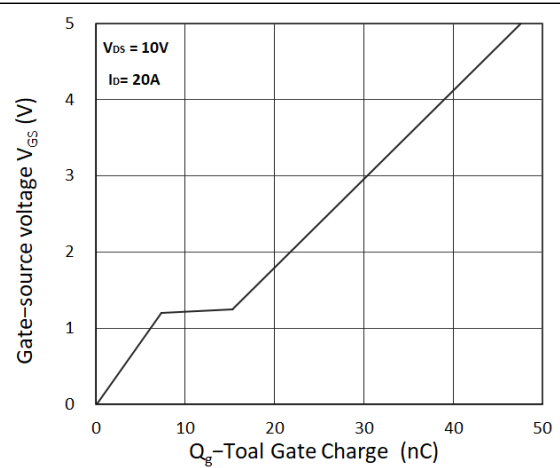


Figure 8. Gate Charge Characteristics

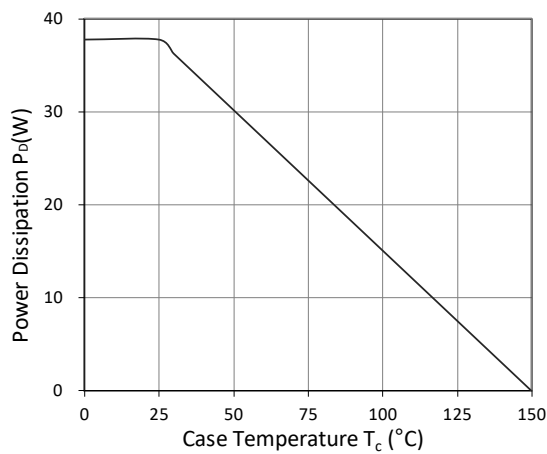


Figure 9. Power Dissipation

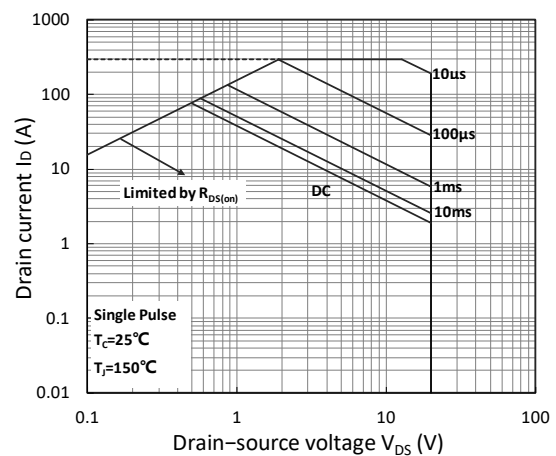


Figure 10. Safe Operating Area

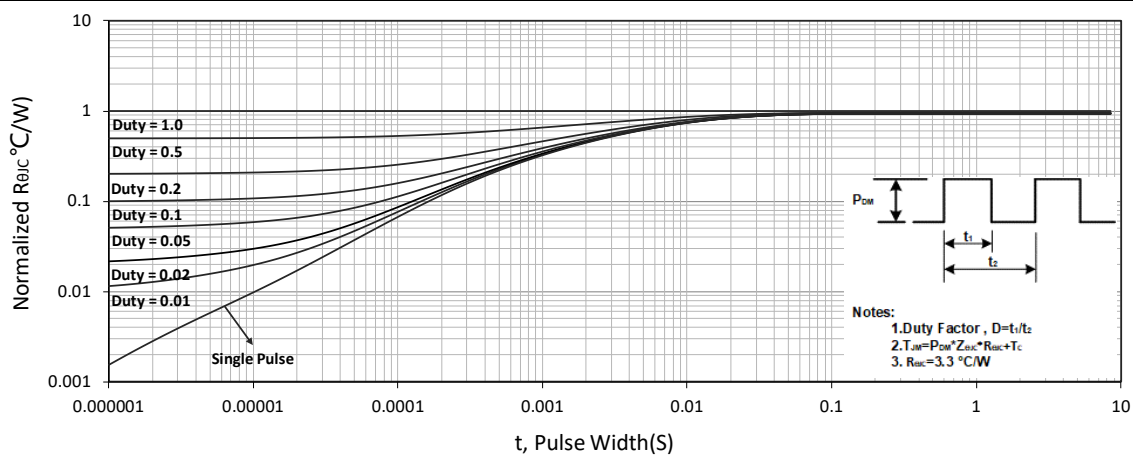


Figure 11. Normalized Maximum Transient Thermal Impedance

Test Circuit

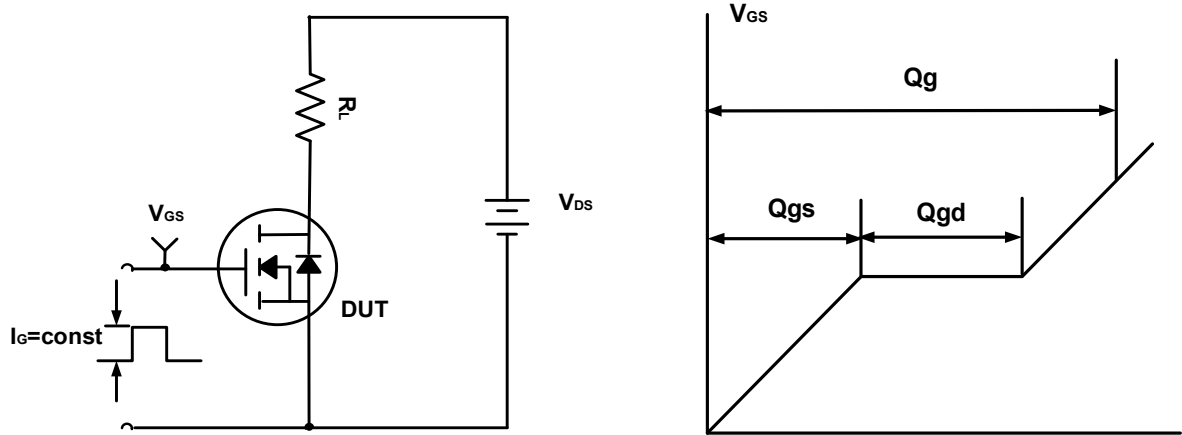


Figure A. Gate Charge Test Circuit & Waveforms

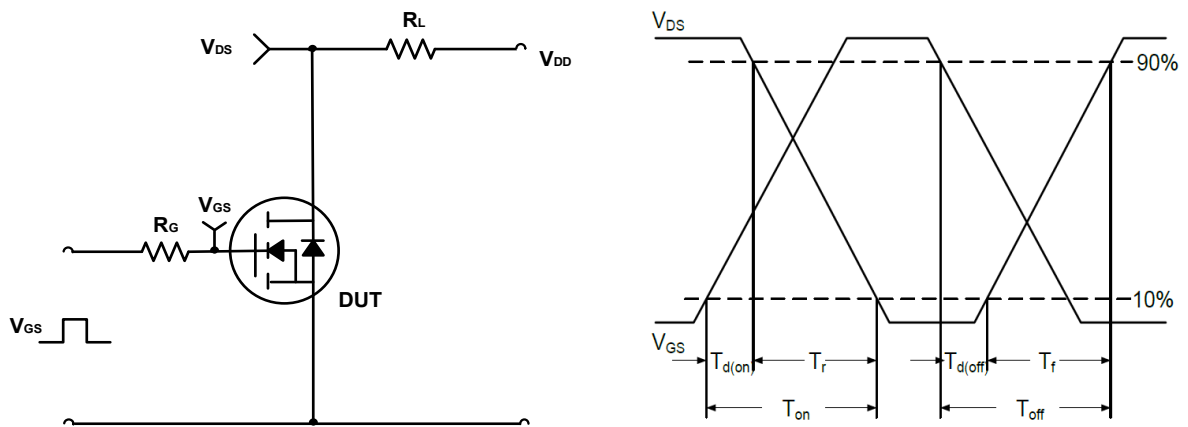


Figure B. Switching Test Circuit & Waveforms

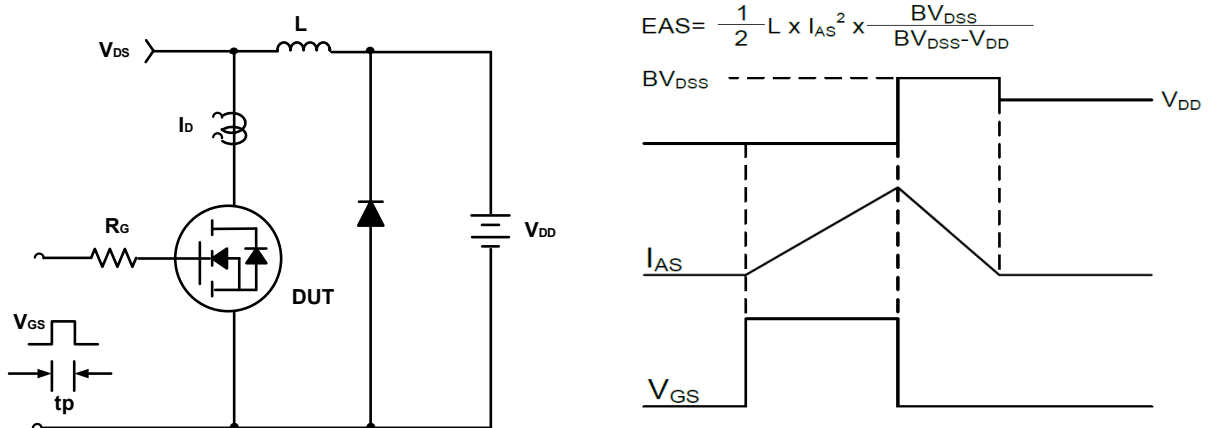
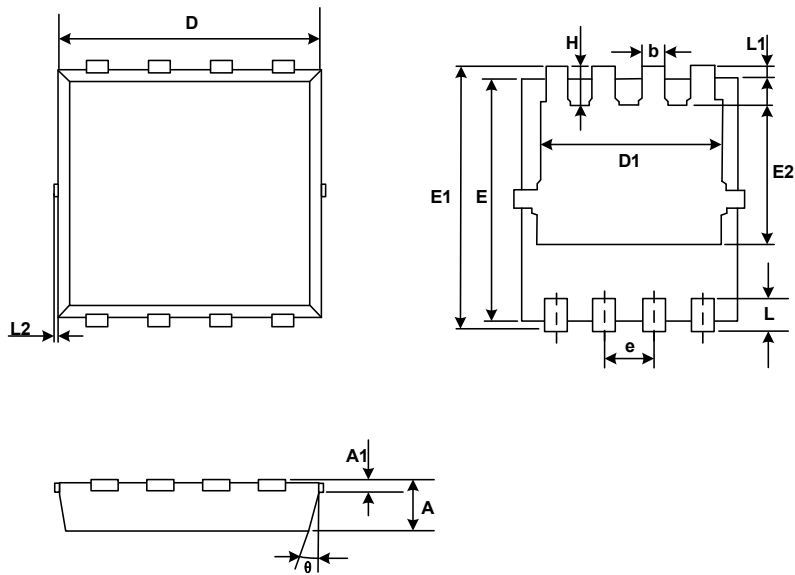


Figure C. Unclamped Inductive Switching Circuit & Waveforms

Mechanical Dimensions for PDFN3030-8L

COMMON DIMENSIONS

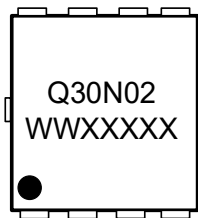


SYMBOL	MM	
	MIN	MAX
A	0.65	0.90
A1	0.10	0.25
D	2.90	3.25
D1	2.25	2.69
E	2.90	3.20
E1	3.00	3.60
E2	1.35	2.20
b	0.20	0.40
e	0.65BSC	
L	0.15	0.50
L1	0.13BSC	
L2	0.00	0.20
H	0.15	0.65
θ	0°	14°

Ordering Information

Part	Package	Marking	Packing method
WMQ30N02T1	PDFN3030-8L	Q30N02	Tape and Reel

Marking Information



Q30N02 = Device code
WWXXXXXX= Date code

Contact Information

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WAYON website: <http://www.way-on.com>

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